

<b>Notice of References Cited</b>	Application/Control No. 10/659,744	Applicant(s)/Patent Under Reexamination NABEYAMA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2006/0140637	06-2006	Sakata et al.	398/147
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